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Application No. <u>09/653,411</u>	Prepared by <u>NPB</u>	Tracking Number <u>05,895,991</u>	
Examiner-GAU <u>Eckert - 2815</u>	Date <u>3/10/04</u>	Week Date <u>1/26/04</u>	
	No. of queries <u>2</u>	<u>1PW</u>	

JACKET			
a. Serial No.	f. Foreign Priority	k. Print Claim(s)	p. PTO-1449
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

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k. Other	
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a. Claim(s) Missing	<p><i>Phantasia</i></p> <p>initials <i>OKM</i></p>
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3/30/04



PTO/SB/08A (10-01)

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Substitute for form 1449/APTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)			Complete If Known		
			Application Number	09/653,411	
			Filing Date	August 31, 2000	
			First Named Inventor	Whonchee Lee	
			Art Unit	2815	
			Examiner Name	Joseph H. Nguyen	
Sheet	1	of	3	Attorney Docket Number	M4065.0361/P361

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No.	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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	AC	2002/0025760	02-28-2002	Lee et al.	
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PTO/SB/06A (10-01)

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)			Application Number	09/653,411	
			Filing Date	August 31, 2000	
			First Named Inventor	Whonchee Lee	
			Art Unit	2815	
			Examiner Name	Joseph H. Nguyen	
Sheet	2	of	3	Attorney Docket Number	M4065.0361/P361

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Examiner Initials	Cite No.	Foreign Patent Document Country Code ² -Number ³ -Kind Code ⁴ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁵
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¹ Applicant's unique citation designation number (optional). ² See attached Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the application number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
JN	CA	KONDO, S. et al., "Abrasive-Free Polishing for Copper Damascene Interconnection," Journal of the Electrochemical Society, Vol. 147, No. 10, pp. 3907-3913, (2000)	
	CB	D'HEURLE, F.M. and K.C. PARK, IBM Technical Disclosure Bulletin, Electrolytic Process for Metal Pattern Generation, Vol. 17, No. 1, pp. 271-272, June 1974, XP-002235691, NN 7406271.	
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		Filing Date	August 31, 2000		
		First Named Inventor	Whonchee Lee		
		Group Art Unit	2815		
		Examiner Name	Joseph H. Nguyen		
Sheet	3	of	3	Attorney Docket Number	M4065.0361/P361

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	CI	ATMI, Inc., adapted from a presentation at the Semicon West '99 Low Dielectric Materials Technology Conference, San Francisco, California, July 12, 1999, pp. 13-25.		
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	CK	Micro Photonics, Inc. CSM Nano Hardness Tester [online]. 6 pages. Retrieved from the Internet on July 29, 2002. <URL: http://www.microphotonics.com/nht.html >.		

Examiner Signature	JOSEPH H. NGUYEN	Date Considered	11/10/04
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